HEXFET® Power MOSFET



- Advanced Process Technology
- Isolated Package
- High Voltage Isolation = 2.5KVRMS (5)
- Sink to Lead Creepage Dist. = 4.8mm
- Fully Avalanche Rated
- Lead-Free

$V_{ exttt{DSS}}$	100V
R <sub>DS(on)</sub>	0.036Ω
l <sub>D</sub>	24A

G	D	S
Gate	Drain	Source

## Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low onresistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications

The TO-220 Fullpak eliminates the need for additional insulating hardware in commercial-industrial applications. The moulding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. This isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The Fullpak is mounted to a heatsink using a single clip or by a single screw fixing.

Dood Dort Nive	o Part Number   Package Type			──── Orderable Part Numb		
Base Part Num	nber Package Type	Form	Quantity	Orderable	Part Number	
IRFI1310NPb	F TO-220 Full-Pak	Tube	50	IRFI13	310NPbF	
Absolute Maximu	ım Ratings					
Symbol		meter		Max.	Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub>	@ 10V		24		
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub>	@ 10V	17		Α	
•	D 1 1D 1 0 100			440		

**Standard Pack** 

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V <sub>GS</sub> @ 10V	24	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	17	Α
I <sub>DM</sub>	Pulsed Drain Current ①⑥	140	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	56	W
	Linear Derating Factor	0.37	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally Limited) ②⑥	420	mJ
I <sub>AR</sub>	Avalanche Current ①⑥	22	A
E <sub>AR</sub>	Repetitive Avalanche Energy ①	5.6	mJ
dv/dt	Peak Diode Recovery dv/dt36	5.0	V/ns
$T_J$	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

## Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ hetaJC}$	Junction-to-Case		2.7	°C/W
$R_{ heta JA}$	Junction-to-Ambient		65	C/VV

2017-04-27



# Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions	
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$	
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.11		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA ®	
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.036	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 13A	
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
gfs	Forward Trans conductance	14			S	V <sub>DS</sub> = 25V, I <sub>D</sub> = 22A <sup>©</sup>	
I <sub>DSS</sub>	Drain-to-Source Leakage Current			25 250	μA	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 150 ^{\circ}\text{C}$	
	Gate-to-Source Forward Leakage			100		V <sub>GS</sub> = 20V	
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	nA	V <sub>GS</sub> = -20V	
$Q_g$	Total Gate Charge			120		I <sub>D</sub> = 22A	
$Q_{gs}$	Gate-to-Source Charge			15	nC	$V_{DS} = 80V$	
$Q_{qd}$	Gate-to-Drain Charge			58		V <sub>GS</sub> = 10V , See Fig. 6 and 13@0	
$\mathbf{t}_{d(on)}$	Turn-On Delay Time		11			V <sub>DD</sub> = 50V	
t <sub>r</sub>	Rise Time		56			I <sub>D</sub> =22A	
$t_{d(off)}$	Turn-Off Delay Time		45		ns	$R_G = 3.6\Omega$	
t <sub>f</sub>	Fall Time		40			R <sub>D</sub> = 2.9Ω, See Fig. 10④⑥	
$L_D$	Internal Drain Inductance		4.5		nH	Between lead, 6mm (0.25in.)	
Ls	Internal Source Inductance		7.5		1117	from package and center of die contact	
C <sub>iss</sub>	Input Capacitance		1900			V <sub>GS</sub> = 0V	
C <sub>oss</sub>	Output Capacitance		450		pF	V <sub>DS</sub> = 25V	
C <sub>rss</sub>	Reverse Transfer Capacitance		230		pΕ	f = 1.0MHz, See Fig. 56	
С	Drain to Sink Capacitance		12			f = 1.0MHz	
Source-Drain	Ratings and Characteristics	<u>-</u>					
	Parameter	Min.	Тур.	Max.	Units	Conditions	
I <sub>S</sub>	Continuous Source Current			24		MOSFET symbol	

	Parameter	Min.	Тур.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)			24	_	MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			140		integral reverse p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 13A, V_{GS} = 0V $ ④
t <sub>rr</sub>	Reverse Recovery Time		180	270	ns	$T_J = 25^{\circ}C, I_F = 22A$
Q <sub>rr</sub>	Reverse Recovery Charge		1.2	1.8	μС	di/dt = 100A/μs ④ ⑥
t <sub>on</sub>	Forward Turn-On Time	Intrinsio	turn-on	time is	negligib	le (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )

## Notes:

- $\odot$  starting T<sub>J</sub> = 25°C, L = 1.0mH, R<sub>G</sub> = 25 $\Omega$ , I<sub>AS</sub> = 22A (See fig. 12)
- $\label{eq:local_local_local} \text{$\Im$} \quad I_{SD} \leq 22A, \ di/dt \leq 180A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175^{\circ}C.$
- 4 Pulse width  $\leq 300 \mu s$ ; duty cycle  $\leq 2\%$ .
- ⑤ t=60s, *f*=60Hz
- © Uses IRF1310N data and test conditions.



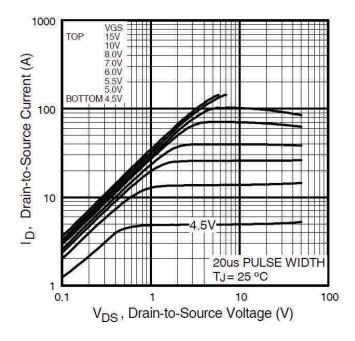


Fig. 1 Typical Output Characteristics

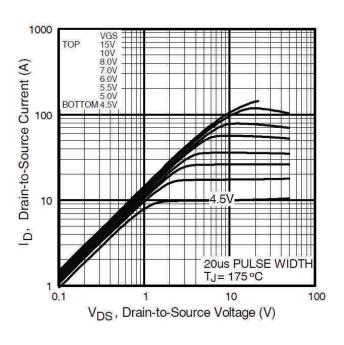


Fig. 2 Typical Output Characteristics

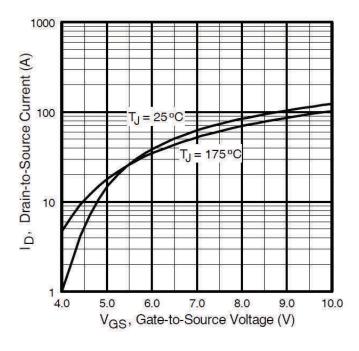
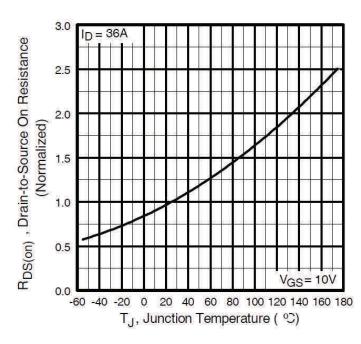
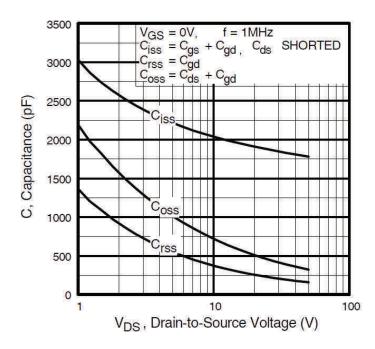


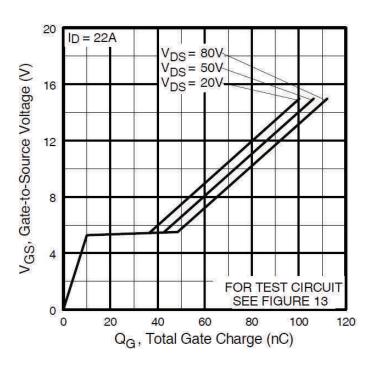
Fig. 3 Typical Transfer Characteristics



**Fig. 4** Normalized On-Resistance vs. Temperature



**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage

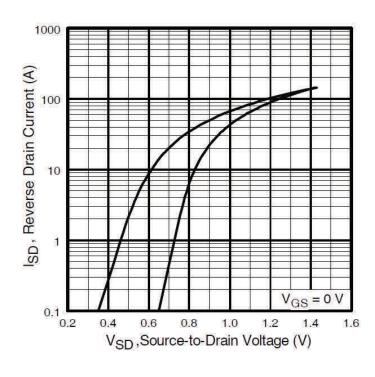


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

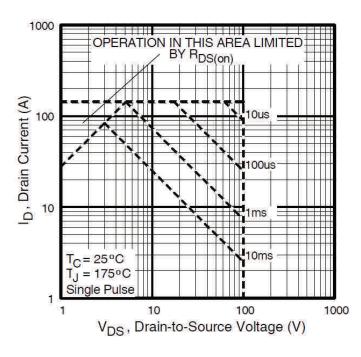


Fig 8. Maximum Safe Operating Area



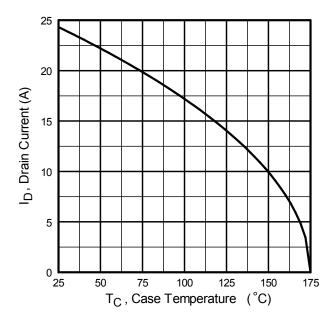


Fig 9. Maximum Drain Current vs. Case Temperature

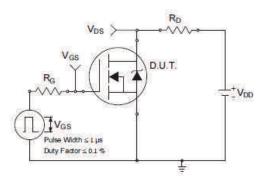


Fig 10a. Switching Time Test Circuit

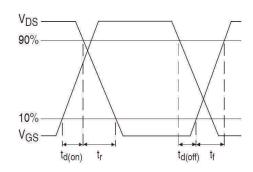


Fig 10b. Switching Time Waveforms

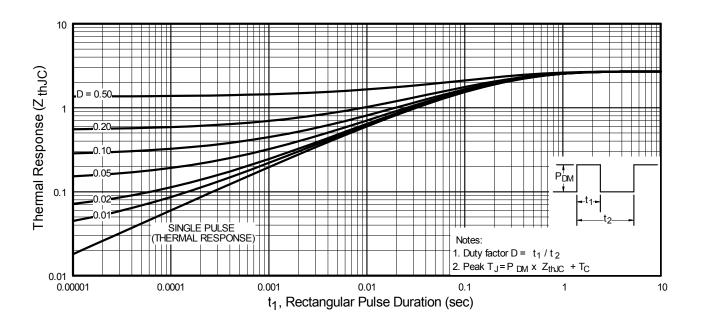


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



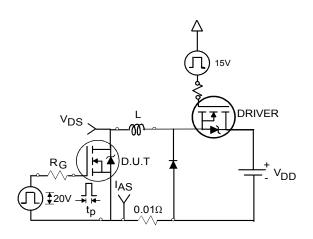


Fig 12a. Unclamped Inductive Test Circuit

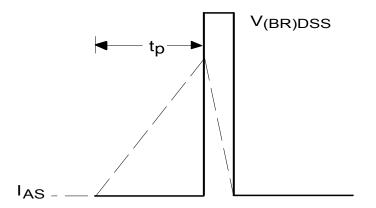


Fig 12b. Unclamped Inductive Waveforms

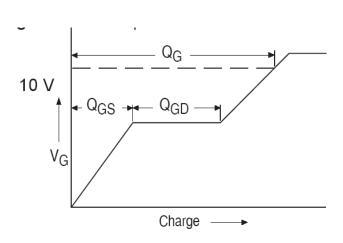
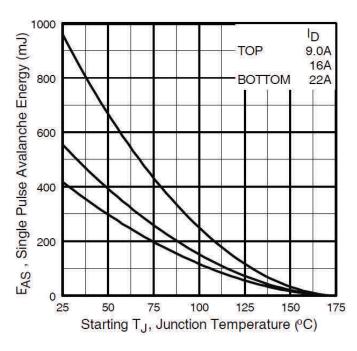


Fig 13a. Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy vs. Drain Current

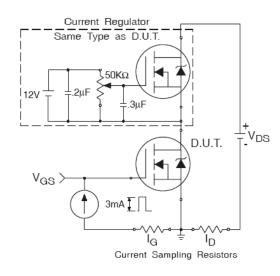
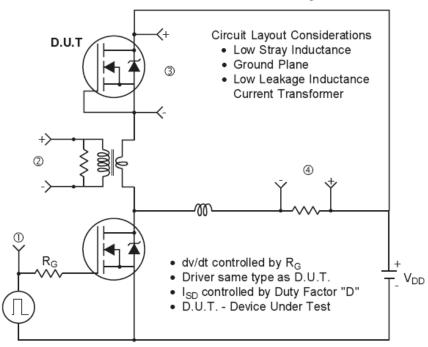


Fig 13b. Gate Charge Test Circuit

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# Peak Diode Recovery dv/dt Test Circuit



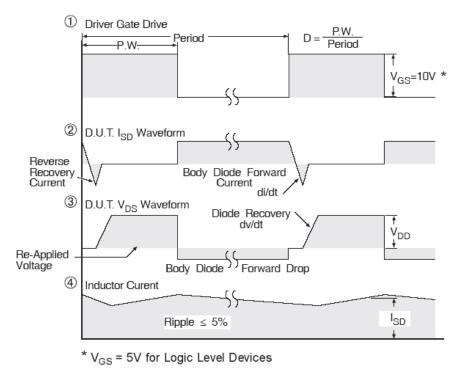
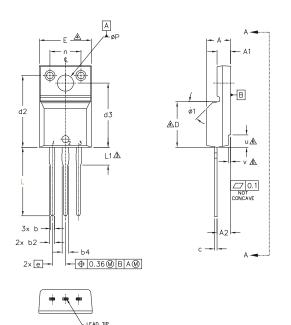
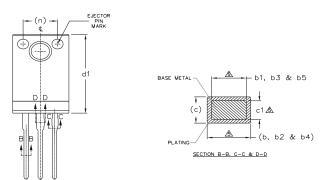


Fig 14. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs



## TO-220 Full-Pak Package Outline (Dimensions are shown in millimeters (inches))





### NOTES:

1.0 DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.

2,0 DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3.0 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.

DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTER MOST EXTREMES OF THE PLASTIC BODY.

6

16.0 STEP OPTIONAL ON PLASTIC BODY DEFINED BY DIMENSIONS u & v.

.O CONTROLLING DIMENSION: INCHES.

S	DIMENSIONS				N
M B O	MILLIM	ETERS	INC	HES	O T E S
L	MIN.	MAX.	MIN.	MAX.	S
А	4.57	4.83	.180	.190	
A1	2.57	2.82	.101	.111	
A2	2.51	2.92	.099	.115	
b	0.61	0.94	.024	.037	
ь1	0.61	0.89	.024	.035	5
b2	0.76	1.27	.030	.050	
ь3	0.76	1.22	.030	.048	5
b4	1.02	1.52	.040	.060	
b5	1.02	1.47	.040	.058	5
С	0.33	0.63	.013	.025	
с1	0.33	0.58	.013	.023	5
D	8.66	9.80	.341	.386	4
d1	15.80	16.13	.622	.635	
d2	13.97	14.22	.550	.560	
d3	12.29	12.93	.484	.509	
E	9.63	10.74	.379	.423	4
е		BSC		BSC	
L	13.21	13.72	.520	.540	
L1	3.10	3.68	.122	.145	3
n	6.05	6.60	.238	.260	
ØΡ	3.05	3.45	.120	.136	
u	2.39	2.49	.094	.098	6
V	0.41	0.51	.016	.020	6
Ø1	_	45°	_	45°	

## LEAD ASSIGNMENTS

## <u>HEXFET</u>

1.- GATE

2.- DRAIN

3.- SOURCE

## IGBTs, CoPACK

1.- GATE

2.- COLLECTOR

3.- EMITTER

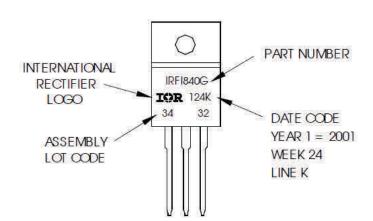
## TO-220 Full-Pak Part Marking Information

EXAMPLE: THIS IS AN IRFI840G WITH ASSEMBLY

LOT CODE 3432

ASSEMBLED ON WW 24, 2001 IN THE ASSEMBLY LINE "K"

Note: "P" in assembly line position indicates "Lead-Free"



TO-220AB Full-Pak packages are not recommended for Surface Mount Application.

Note: For the most current drawing please refer to website at http://www.irf.com/package/



Qualification Information

Qualification Level	Industrial (per JEDEC JESD47F) †		
Moisture Sensitivity Level	TO-220 Full-Pak N/A		
RoHS Compliant	Yes		

† Applicable version of JEDEC standard at the time of product release.

## **Revision History**

Date	Comments	
5/27/2016	<ul> <li>Updated datasheet with corporate template.</li> <li>Added disclaimer on last page.</li> </ul>	
04/27/2017	Corrected Package Outline on page 8.	

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Trademarks updated November 2015

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